



Product Change Notification / ASER-13ZAYE268

Date:

08-Jul-2022

Product Category:

Microprocessors

PCN Type:

Manufacturing Change

Notification Subject:

CCB 4902 & 4902.001 Final Notice: Qualification of a new die size and mold compound for Die # 2 for selected catalog part numbers (CPN) ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR, ATSAMA5D27C-D5M-CU & ATSAMA5D27C-D5M-CUR available in 289L TFBGA (14x14x1.2mm) and U2 component for selected catalog part number (CPN) ATSAMA5D27-SOM1 available in 176L MODULE (40x38x6.34mm) packages.

Affected CPNs:

[ASER-13ZAYE268_Affected_CPN_07082022.pdf](#)

[ASER-13ZAYE268_Affected_CPN_07082022.csv](#)

Notification Text:

PCN Status:Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of a new die size and mold compound for Die # 2 for selected catalog part numbers (CPN) ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR, ATSAMA5D27C-D5M-CU & ATSAMA5D27C-D5M-CUR available in 289L TFBGA (14x14x1.2mm) and U2 component for selected catalog part number (CPN) ATSAMA5D27-SOM1 available in 176L MODULE (40x38x6.34mm) packages.

Pre and Post Change Summary:

	Pre Change	Post Change
Die Size	With change in die size. See Pre and Post Change Summary for comparison.	
Mold Compound	KE-G1250LKDS	KE-G1250NAS

Impacts to Data Sheet:None**Change Impact:**None**Reason for Change:**To improve manufacturability by qualifying a new die size and new mold compound.**Change Implementation Status:**In Progress**Estimated First Ship Date:**July 15, 2022 (date code: 2229)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Time Table Summary:

	July 2022				
Workweek	27	28	29	30	31
Qual Report Availability		x			
Final PCN Issue Date		x			
Estimated Implementation Date			x		

Method to Identify Change:Traceability code**Qualification Report:**Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.**Revision History:**July 8, 2021: Issued final notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

[PCN ASER-13ZAYE268_Qual Report.pdf](#)

[PCN_ASER-13ZAYE268_Pre and Post Change_Summary.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

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If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

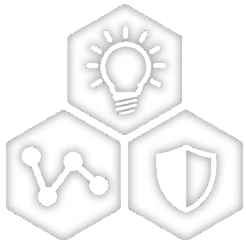
ASER-13ZAYE268 - CCB 4902 & 4902.001 Final Notice: Qualification of a new die size and mold compound for Die # 2 for selected catalog part numbers (CPN) ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR, ATSAMA5D27C-D5M-CU & ATSAMA5D27C-D5M-CUR available in 289L TFBGA (14x14x1.2mm) and U2 component for selected catalog part number (CPN) ATSAMA5D27-SOM1 available in 176L MODULE (40x38x6.34mm) packages.

ATSAMA5D27C-D5M-CU
ATSAMA5D27C-D5M-CUR
ATSAMA5D28C-D1G-CU
ATSAMA5D27C-D1G-CU
ATSAMA5D28C-D1G-CUR
ATSAMA5D27C-D1G-CUR
ATSAMA5D27-SOM1

CCB 4902 & 4902.001
Pre and Post Change Summary
PCN#: ASER-13ZAYE268



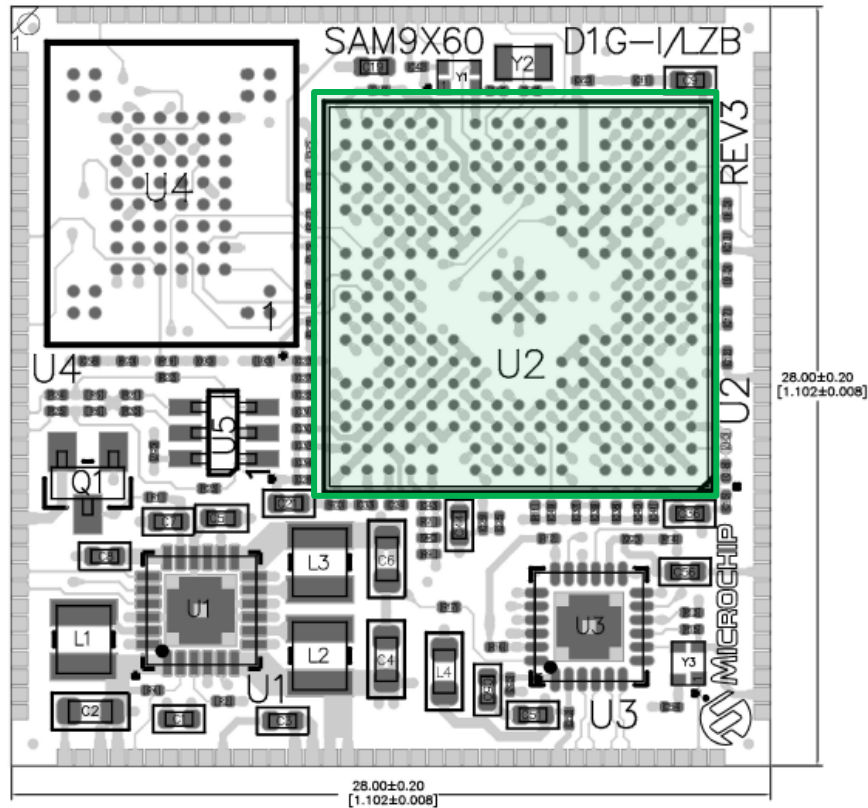
A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



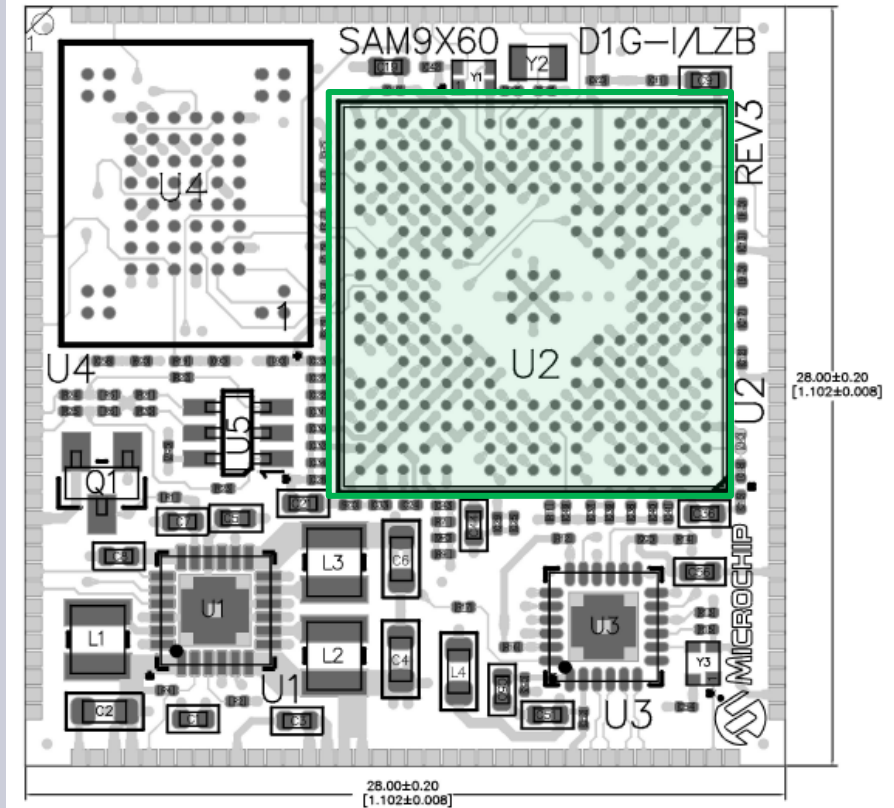
SMART | CONNECTED | SECURE

Pre and Post Change Comparison - ATSAMA5D27-SOM1

Pre change



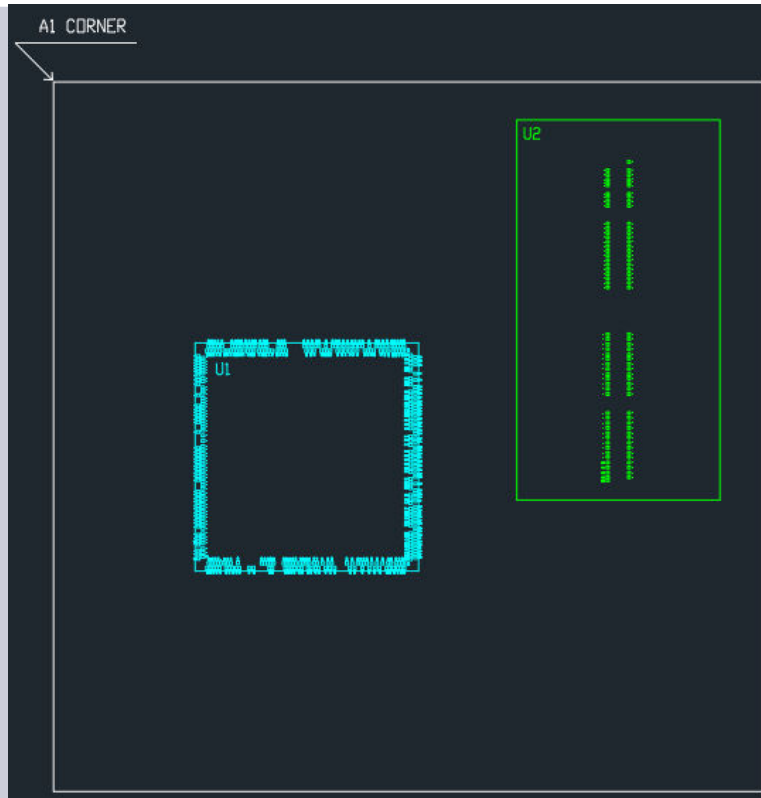
Post Change



Note: Not-to-scale

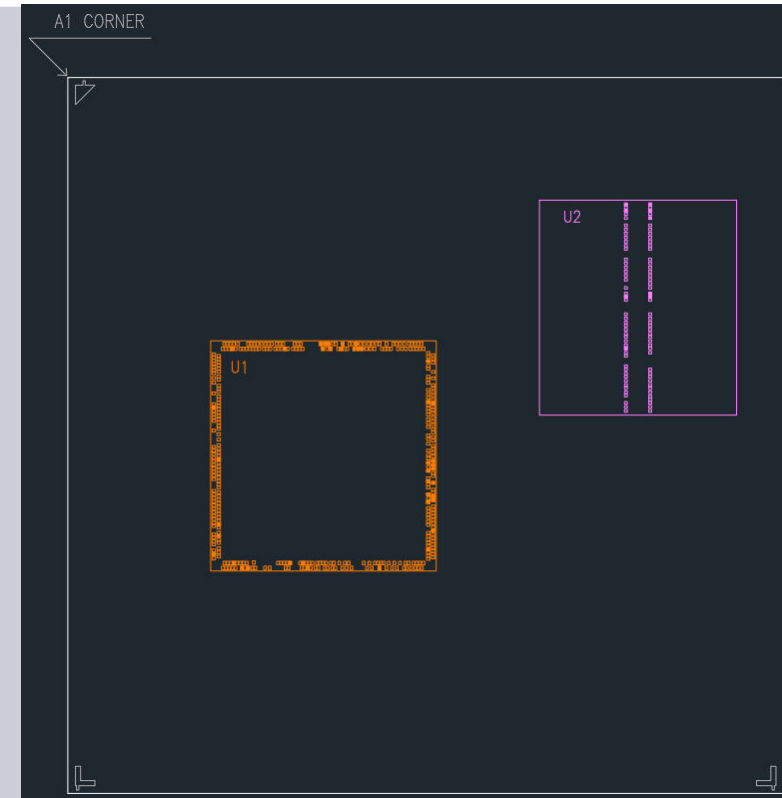
Pre and Post Change Comparison - ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR

Pre change



U2 size : 153.2x290.6mils

Post Change

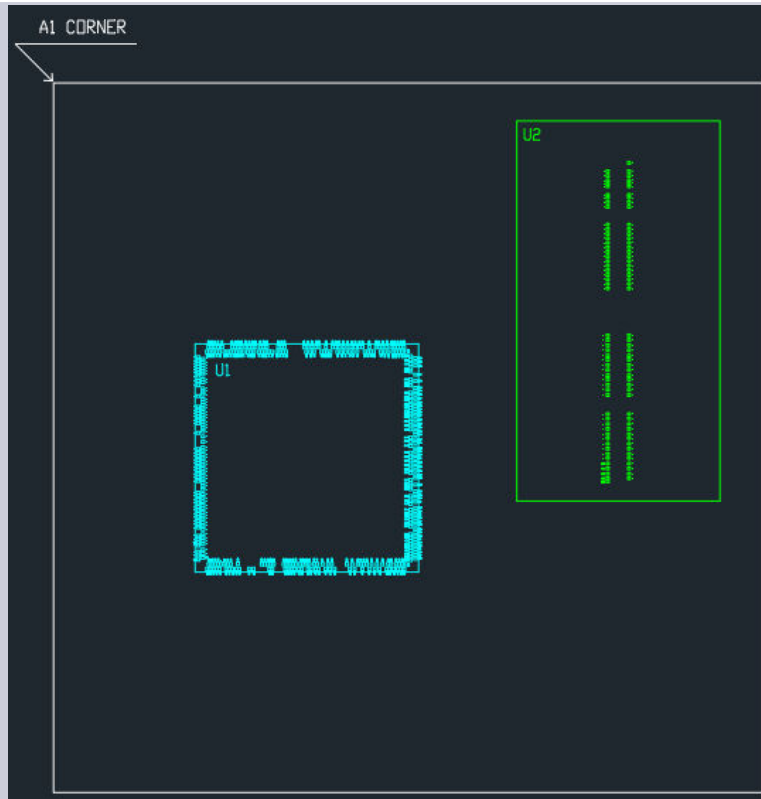


U2 size : 150.3x164 mils

Note: Not-to-scale

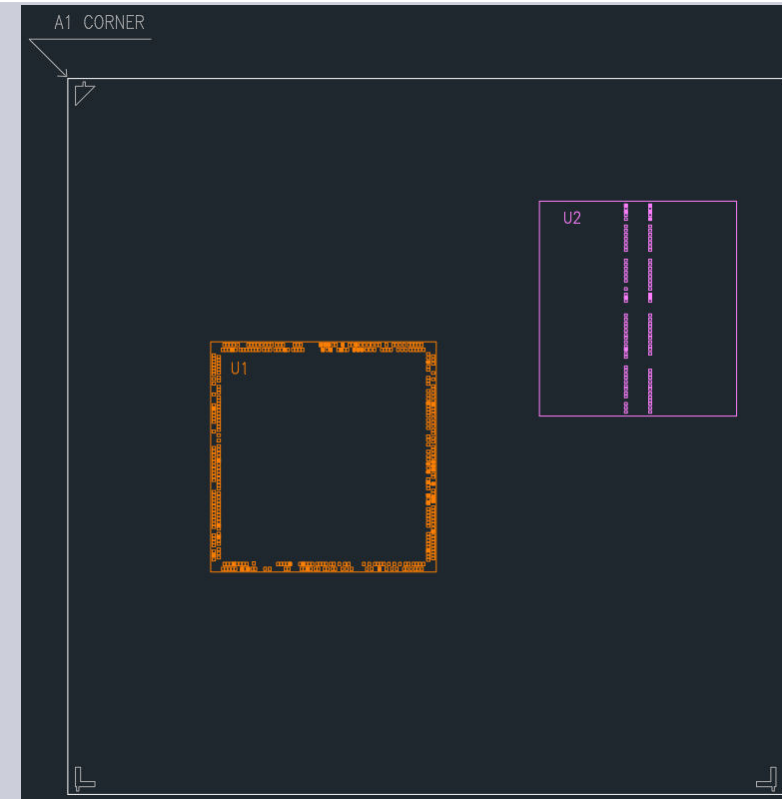
Pre and Post Change Comparison - ATSAMA5D27C-D5M-CU, ATSAMA5D27C-D5M-CUR

Pre change



U2 size : 160.07x160.7mils

Post Change



U2 size : 109.1x129.6 mils

Note: Not-to-scale



QUALIFICATION REPORT SUMMARY

PCN #: ASER-13ZAYE268

**Date:
April 20, 2022**

Qualification of a new die size and mold compound for Die # 2 for selected catalog part numbers (CPN) ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR, ATSAMA5D27C-D5M-CU & ATSAMA5D27C-D5M-CUR available in 289L TFBGA (14x14x1.2mm) and U2 component for selected catalog part number (CPN) ATSAMA5D27-SOM1 available in 176L MODULE (40x38x6.34mm) packages.



MICROCHIP Package Qualification Report

Purpose: Qualification of a new die size and mold compound for Die # 2 for selected catalog part numbers (CPN) ATSAMA5D28C-D1G-CU, ATSAMA5D27C-D1G-CU, ATSAMA5D28C-D1G-CUR, ATSAMA5D27C-D1G-CUR, ATSAMA5D27C-D5M-CU & ATSAMA5D27C-D5M-CUR available in 289L TFBGA (14x14x1.2mm) and U2 component for selected catalog part number (CPN) ATSAMA5D27-SOM1 available in 176L MODULE (40x38x6.34mm) packages.

CCB: 4902 & 4902.001

<u>Misc.</u>	Assembly site	ASEK
	BD Number	BD-000186-01_289L_TFBGA_4BB_ASE
	MP Code (MPC)	3413A74BBD02
	Part Number (CPN)	ATSAMA5D28C-D1G-CU
	MSL information	MSL 3, 260C
	Reliability Site	MPHIL
	Qual ID	QTP4581 Rev. A
<u>Substrate</u>	Core Material	CCL-HL832NX (A-HS)
	Core Thickness	0.26mm
	Part Number	A30115-0
	SM Material	AUS308
	Paddle Size #1	211X214 mils
	Paddle Size #2	192x368 mils
	Number of Layers	4
<u>Bond Wire</u>	Material	CuPdAu
<u>Die Attach</u>	Part Number (Die1)	ATB-125
	Conductive	Non-Conductive
	Part Number (Die2)	ATB-125
	Conductive	Non-Conductive
<u>MC</u>	Part Number	KE-G1250NAS
<u>PKG</u>	PKG Type	289 TFBGA
	PKG width/size	14x14
	Solder Ball Material	SAC1205 (LF35)



MICROCHIP

Package Qualification Report

Manufacturing Information

Lot	Assembly Lot #
1	ASE223100048.000
2	ASE223100047.000
3	ASE223100046.000

Result



Pass



Fail



SAMA5D2 (92U03) with DDR2 25nm 1Gb (Side by Side) device using 289 Balls TFBGA 14x14mm at ASEK pass reliability test per AEC-Q006 which was conducted at MPHL rel lab. This package qualified Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard / Method	Qty. (Acc.)	Def/SS	Result	Remarks
Precondition Prior Perform Reliability Tests (At MSL Level 3)	Electrical Test : 25°C, 85°C System: D10 tester / Thermonics	JESD22-A113	231 units per lot	Lot 1 0/265	Pass	
	Bake 150°C, 24 hrs System: HERAEUS			Lot 2 0/265	Pass	
	30°C/60%RH Moisture Soak 192hrs. System: Climats Excal 5423-HE	IPC/JEDEC J-STD-020E		Lot 3 0/265	Pass	
	3x Convection-Reflow 260°C max System: Mancorp CR.5000F					
Temperature Cycle	Electrical Test : 25°C, 85°C System: D10 Tester / Thermonics					
	Stress Condition: (Standard) -55°C to +125°C, 500 Cycles System: Votsch VTS ² 7012	JESD22-A104	77 units per lot	Lot 1 0/90	Pass	
				Lot 2 0/89	Pass	
				Lot 3 0/90	Pass	
	Acoustic Microscopy		22 units per lot	Lot 1 0/22	Pass	
				Lot 2 0/22	Pass	
				Lot 3 0/22	Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5	Pass	
				Lot 2 0/5	Pass	
				Lot 3 0/5	Pass	
	Bond Strength: 3 units per test Wire Pull (>4.0g) Bond <i>Shear</i> (>10g) Stitch Pull (>3g) System: Dage		6 units per lot	Lot 1 0/6	Pass	
				Lot 2 0/6	Pass	
				Lot 3 0/6	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temperature Cycle	Stress Condition: (Standard) -55°C to +125°C, 1000 Cycles System: Votsch VTS ² 7012	JESD22- A104	70 units per lot	Lot 1 0/79	Pass	
				Lot 2 0/78	Pass	
	Electrical Test : 85°C System: D10 Tester / Thermonics			Lot 3 0/77	Pass	
	Acoustic Microscopy		22 units per lot	Lot 1 0/22	Pass	
				Lot 2 0/22	Pass	
HAST				Lot 3 0/22	Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5	Pass	
				Lot 2 0/5	Pass	
				Lot 3 0/5	Pass	
	Bond Strength: 3 units per test Wire Pull (>4.0g) Bond <i>Shear</i> (>10g) Stitch Pull (>3g) System: Dage		6 units per lot	Lot 1 0/6	Pass	
HAST				Lot 2 0/6	Pass	
				Lot 3 0/6	Pass	
	Stress Condition: (Standard) +110°C/85%RH, 264 hrs System: HIRAYAMA HASTEST PC-422R8	JESD22- A118	77 units per lot	Lot 1 0/90	Pass	
				Lot 2 0/90	Pass	
	Electrical Test : 25°C, 85°C System: D10 Tester / Thermonics			Lot 3 0/90	Pass	
HAST	Acoustic Microscopy		22 units per lot	Lot 1 0/22	Pass	
				Lot 2 0/22	Pass	
				Lot 3 0/22	Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5	Pass	
				Lot 2 0/5	Pass	
HAST				Lot 3 0/5	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
HAST	Bond Strength: 3 units per test Wire Pull (>4.0g) Bond <i>Shear</i> (>10g) Stitch Pull (>3g) System: Dage		6 units per lot	Lot 1 0/7	Pass	
				Lot 2 0/6	Pass	
				Lot 3 0/6	Pass	
	Stress Condition: (Standard) +110°C/85%RH, 528 hrs System: HIRAYAMA HASTEST PC-422R8	JESD22-A118	70 units per lot	Lot 1 0/79	Pass	
				Lot 2 0/79	Pass	
				Lot 3 0/79	Pass	
	Acoustic Microscopy		22 units per lot	Lot 1 0/22	Pass	
				Lot 2 0/22	Pass	
				Lot 3 0/22	Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5	Pass	
				Lot 2 0/5	Pass	
				Lot 3 0/5	Pass	
	Bond Strength: 3 units per test Wire Pull (>4.0g) Bond <i>Shear</i> (>10g) Stitch Pull (>3g) System: Dage		6 units per lot	Lot 1 0/6	Pass	
				Lot 2 0/6	Pass	
				Lot 3 0/6	Pass	
	Stress Condition: (Standard) +110°C/85%RH, 264 hrs. no bias System: HIRAYAMA HASTEST PC-422R8	JESD22-A118	77 units per lot	Lot 1 0/84	Pass	
				Lot 2 0/85	Pass	
				Lot 3 0/85	Pass	
UHAST	Stress Condition: (Standard) +110°C/85%RH, 528 hrs. no bias System: HIRAYAMA HASTEST PC-422R8	JESD22-A118	70 units per lot	Lot 1 0/84	Pass	
				Lot 2 0/85	Pass	
				Lot 3 0/85	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
HTSL	Stress Condition: Bake 150°C, 504 hrs. System: HERAEUS Electrical Test : 25°C, 85°C System: D10 Tester / Thermonics	JESD22-A10	45 units per lot	Lot 1 0/59 Lot 2 0/60 Lot 3 0/65	Pass Pass Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5 Lot 2 0/5 Lot 3 0/5	Pass Pass Pass	
	Stress Condition: Bake 150°C, 1008 hrs. System: HERAEUS Electrical Test : 25°C, 85°C System: D10 Tester / Thermonics	JESD22-A103	44 units per lot	Lot 1 0/54 Lot 2 0/55 Lot 3 0/60	Pass Pass Pass	
	Internal Package Analysis / Cross-section		5 units per lot	Lot 1 0/5 Lot 2 0/5 Lot 3 0/5	Pass Pass Pass	
Bond Strength	Wire Pull (>4.0g) Bond <i>Shear</i> (>10g) Stitch Pull (>3g) System: Dage		5 units 3 lots 30 bonds		Pass	
Physical Dimension	Physical Dimension, 10 units per 3 lots	JESD22 B100 and B108	10 units per lot	30	Pass	